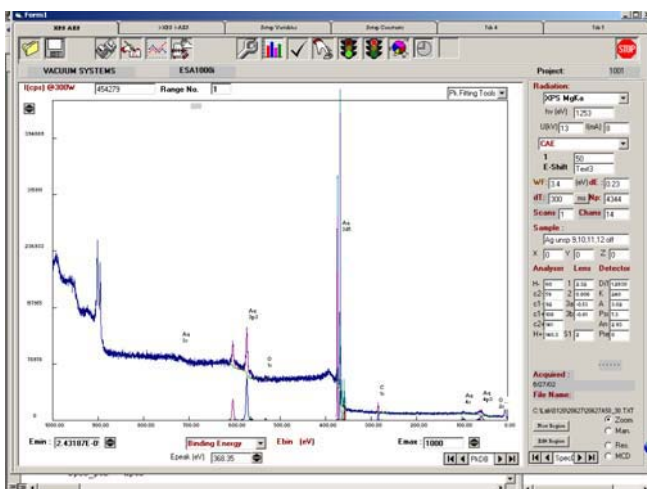


AXPS 2000 Combined Analysis in One Module

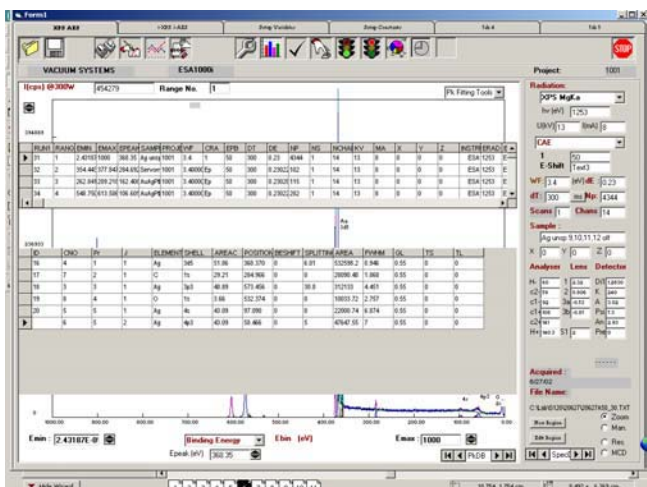


vsanalysis

Our software has an intuitive customer interface, is flexible and easy to use. Its standardized data transfer is ready to accommodate future developments.



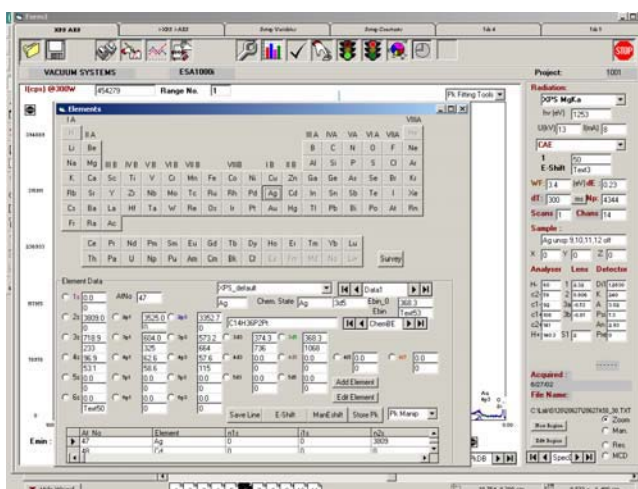
Spectrum acquisition sheet with command buttons: open, save, print, peak & chemical state analysis, instrument setup, bar chart, spectrum setup, start, stop, peak fit, spectrum & energy range parameters



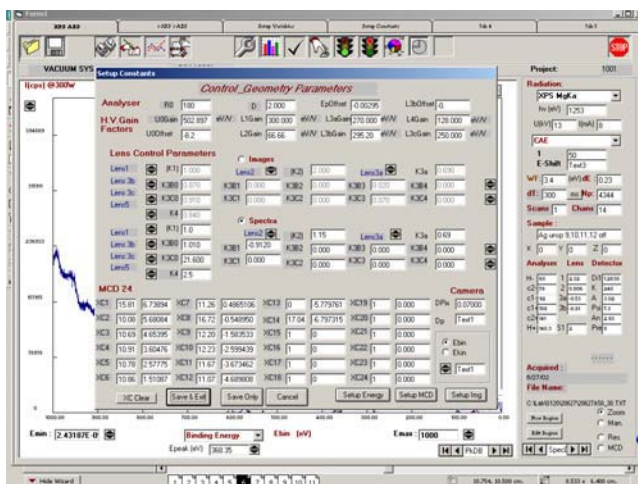
To assist spectrum acquisition, two tables of energy range parameters and peak fitting parameters are available from the main sheet.

Data acquisition

- Combined spectra and chemical map acquisition and processing
- XPS database with sensitivity factors for 50000 Elements and chemical states
- Automatic peak fitting & background modeling (Linear, Shirley, Tougaard)
- Data compatible with 3rd party software



Intuitively designed XPS database table with sensitivity factors for elements & chemical states.



Software controlled instrument set up covering lens zooms, imaging modes, analyzer parameters, gain & offsets of HV modules etc.

VS MicroAnalysis

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Tel. (+44) -1892-665633, Fax (+44) -1892-665648 email krizek@vacsys.co.uk, www.vacsys.co.uk

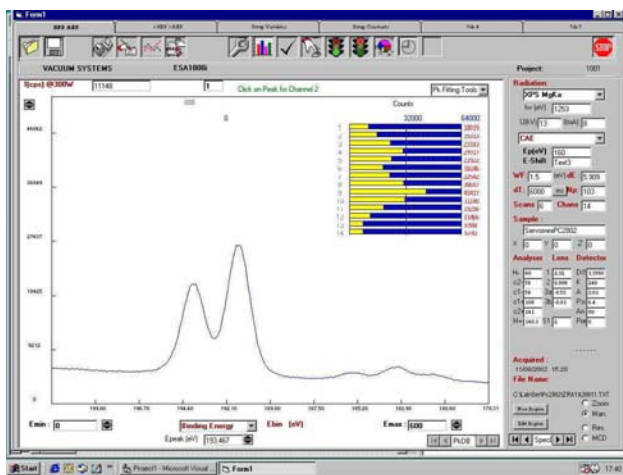
AXPS 2000 Combined Analysis in One Module



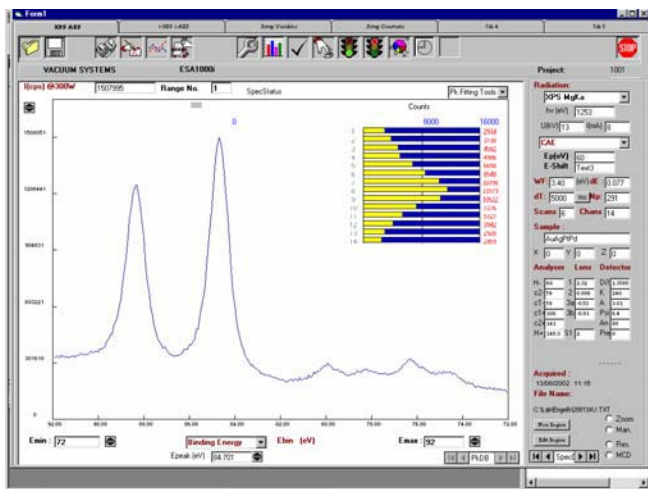
vsµanalysis

Comprehensive analysis by combining XPS spectra , XPS snap-shots and XPS imaging in one instrument .

UPS/XPS AES snap shots



XPS snap shots are available in the form of a bar chart and can be combined intuitively with the XPS spectrum. A simple click on the spectrum chart adjusts the spectrometer and displays the bar chart snap shot at that energy setting. This example shows a profile of the Zr 3d5 peak with 14 channels.



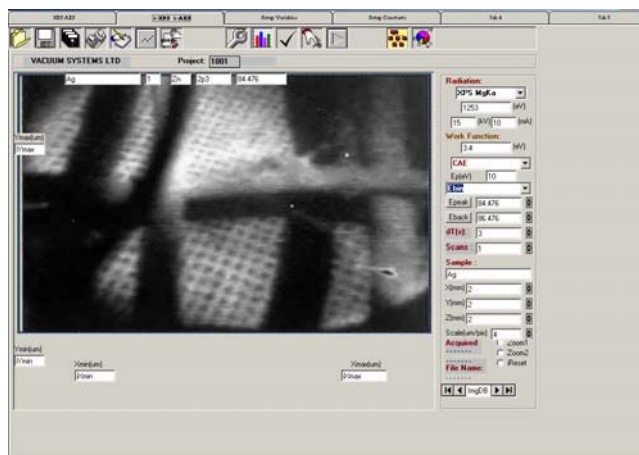
XPS snap-shot intensity profile of Au 4f7 peak

ARXPS application: non-destructive thickness measurement of surface layers

The input lens systems , the analyzer and the detector area are designed to image at solid angles (± 25 degrees standard, 30 degrees optional) that enable angle resolved ARXPS without tilting the sample.

Image acquisition

One of the requirements of a modern XPS system is to combine chemical maps with XPS spectrum acquisition



Advanced image acquisition is integrated within the same package as spectrum software with easy access to both methods.

One click can set the analyzer to any of the required XPS line peak energy retrieved from the 32000 data long database of chemical substances and their XPS and AES lines.

The output data form is compatible with the third party software for easy data base access, report generation or image processing and manipulation.

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